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#### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: Unassigned Examiner: Unassigned

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Applicant(s)	:	Junichi HIKITA et al.	)	
Serial No.	:	Divisional of Appl. Serial No. 09/499,384	)	
Filed	:	March 11, 2004	) )	INFORMATION DISCLOSURE
For	:	SEMICONDUCTOR CHIP AND PRODUCTION THEREOF, AND SEMICONDUCTOR DEVICE HAVING SEMICONDUCTOR CHIP BONDED TO SOLID DEVICE	, ) ) )	<u> </u>
Attorney Ref.	:	AI 257 D1	) )_	

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure, attached are copies of the Forms PTO-1449 from the parent application, serial number, **09/499,384**, which the Examiner may wish to consult during examination of this Divisional Application thereof.

Respectfully submitted,

March 11, 2004

Date

Steven M. Rabin (Reg. No. 29.102)

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#### Application/Control No. Applicant(s)/Patent Under Reexamination 09/499,384 HIKITA ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Hung K. Vu 2811 **U.S. PATENT DOCUMENTS Document Number** Date Country Code-Number-Kind Code MM-YYYY Name Classification US-5,269,453 12-1993 Melton et al. 228/180.22 US-В US-С US-D Ε US-US-F G US-USн US-1 US-J US-Κ US-ŲS FOREIGN PATENT DOCUMENTS **Document Number** Date Country Code-Number-Kind Code Country Name MM-YYYY Classification N 0 431... Ρ Q R S T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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